

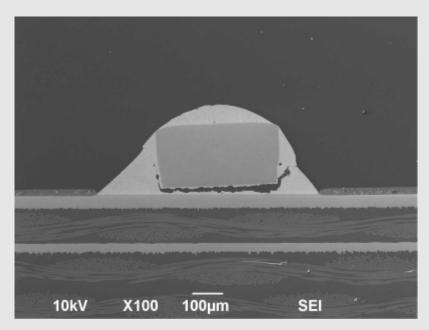
SEM/EDX/Optical Microscope Applications

Reliability Engineering Group Cascade Engineering Services, Inc. 6640 185th Ave NE Redmond WA 98052 (425) 895-8617 x 564

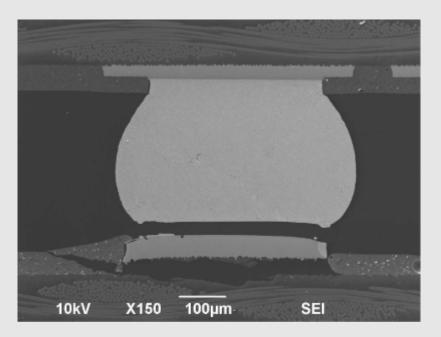
www.cascade-eng.com



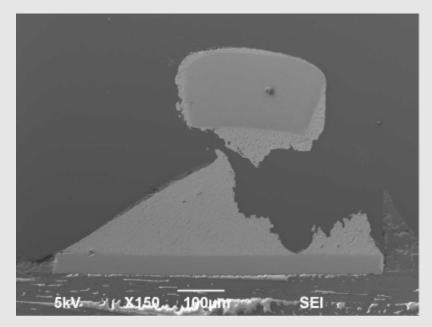
Example Defects Captured from SEM Imaging



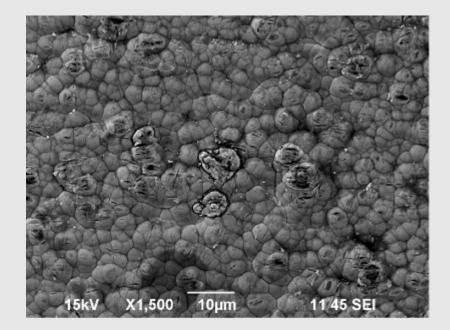
Connector Pin Cracking from Mechanical Overstress Tests



BGA Lead Free Solder Joint Delamination from Mechanical Bend Test



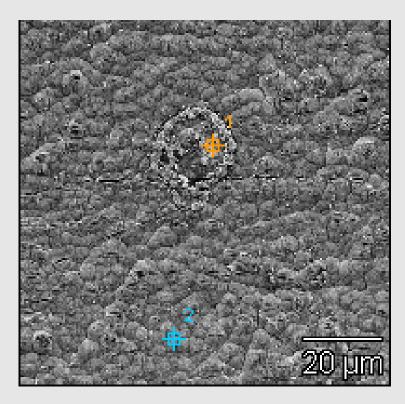
Solder Joint Overstress Fracture from Mechanical Bend Tests

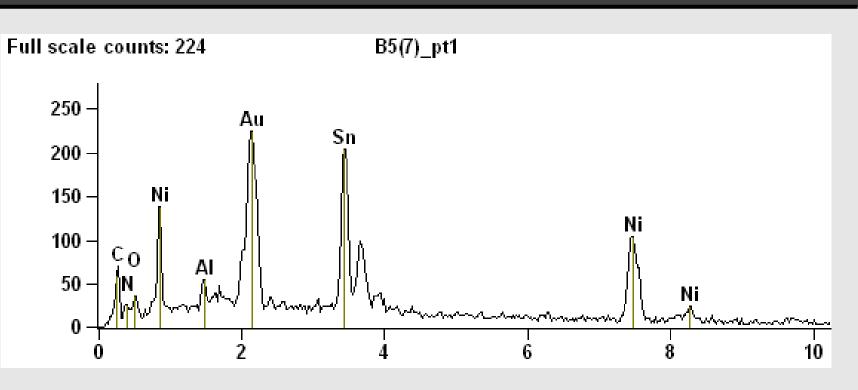


Surface contamination in gold plated PCB board

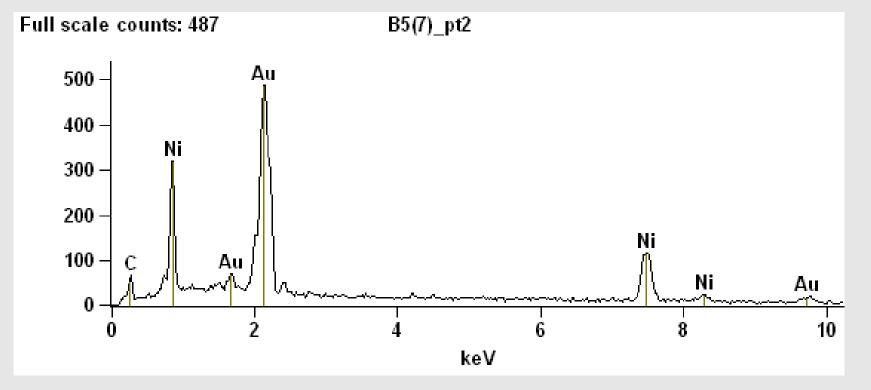


EDX Analysis of Ni / Au Plated PCBA





Connector Pin Cracking from Mechanical Overstress Tests





Dye and Pry Analysis of CPU from a Motherboard

Equipment Used

• Optical Microscope with EFI (3D Stitching) Capability

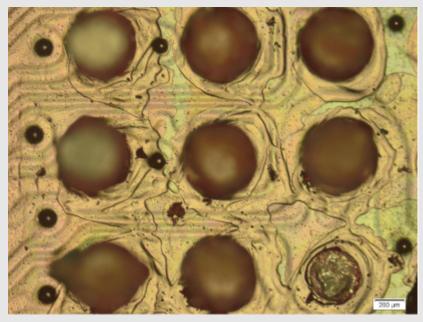


Image Focus: bottom edge i.e PCBA

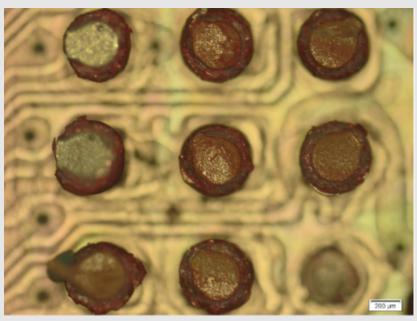
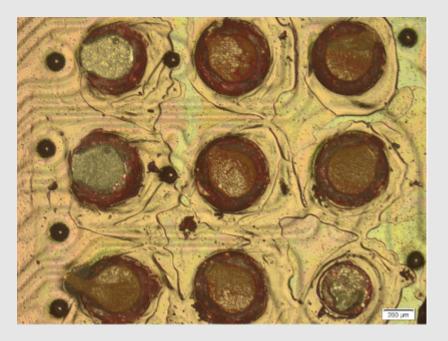


Image Focus: top edge i.e fractured joint top



Composite Extended Focal Image; Good Focus for both top and bottom edges enabling better failure analysis